TOSHIBA Transistor Silicon NPN Epitaxial Type

2SC3474

Switching Applications Solenoid Drive Applications

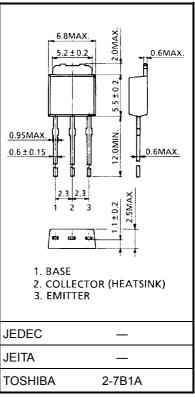
- High DC current gain: $h_{FE} = 500$ (min) ($I_{C} = 400$ mA)
- Low saturation voltage: VCE (sat) = 0.5 V (max) (IC = 300 mA)

Maximum Ratings (Ta = 25°C)

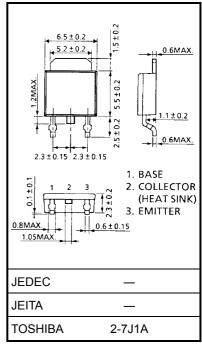
Characteristics		Symbol	Rating	Unit	
Collector-base voltage		V_{CBO}	80	V	
Collector-emitter voltage		V _{CEO}	80	V	
Emitter-base voltage		V _{EBO}	7	V	
Collector current		IC	2	Α	
Base current		Ι _Β	0.5	Α	
Collector power dissipation	Ta = 25°C	D-	1.0	W	
	Tc = 25°C	P _C	20		
Junction temperature		Tj	150	°C	
Storage temperature range		T _{stg}	−55 to 150	°C	

Industrial Applications

Unit: mm



Weight: 0.36 g (typ.)

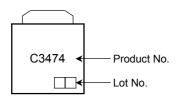


Weight: 0.36 g (typ.)

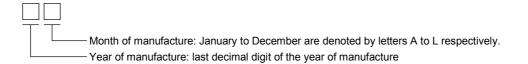
Electrical Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off of	current	I _{CBO}	V _{CB} = 80 V, I _E = 0	_	_	1	μΑ
Emitter cut-off cu	rrent	I _{EBO}	V _{EB} = 7 V, I _C = 0	_	_	1	μΑ
Collector-emitter	breakdown voltage	V (BR) CEO	I _C = 10 mA, I _B = 0	80	_	_	V
DC current gain		h _{FE}	V _{CE} = 1 V, I _C = 400 mA	500	_	_	
Collector-emitter	saturation voltage	V _{CE} (sat)	I _C = 300 mA, I _B = 1 mA	_	0.3	0.5	V
Base-emitter satu	uration voltage	V _{BE} (sat)	I _C = 300 mA, I _B = 1 mA	_	_	1.1	V
Transition freque	ncy	f _T	V _{CE} = 2 V, I _C = 100 mA	_	85	_	MHz
Collector output capacitance		C _{ob}	V _{CB} = 10 V, I _E = 0, f = 1 MHz	_	50	_	pF
Switching time Storage	Turn-on time	t _{on}	20 μs B1 OUTPUT Ca Se Ca Ca Ca Ca Ca Ca Ca C	_	2	_	
	Storage time	t _{stg}		_	5	_	μs
	Fall time	t _f	I _{B1} = -I _{B2} = 1 mA, DUTY CYCLE ≤ 1%	_	2	_	

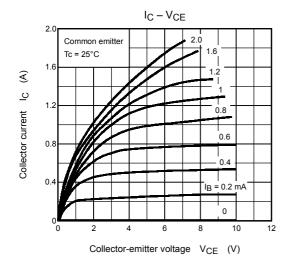
Marking

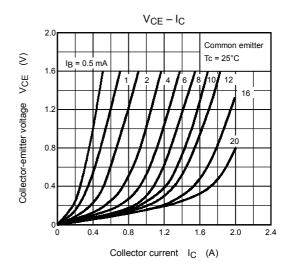


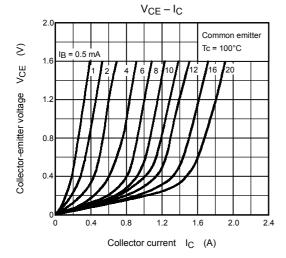
Explanation of Lot No.

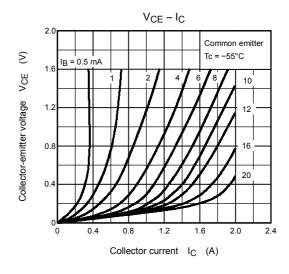


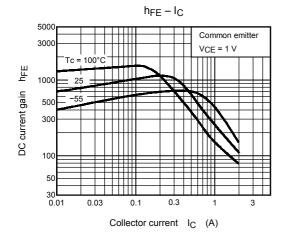
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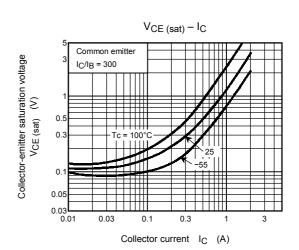




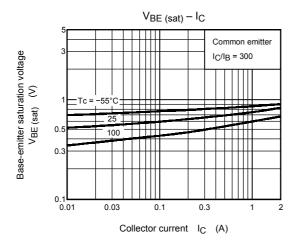


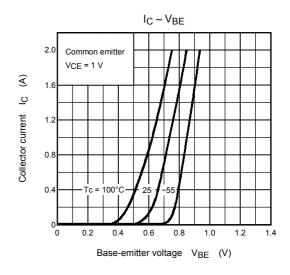


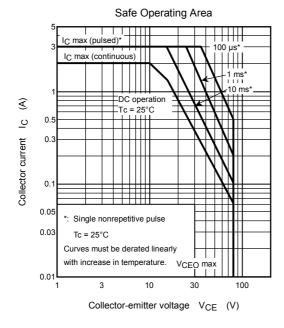


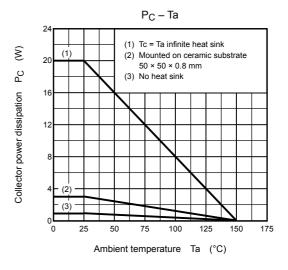


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